



## A617308 Series

**Preliminary**

**128K X 8 BIT HIGH SPEED CMOS SRAM**

---

### Document Title

**128K X 8 BIT HIGH SPEED CMOS SRAM**

### Revision History

<u>Rev. No.</u>	<u>History</u>	<u>Issue Date</u>	<u>Remark</u>
0.0	Initial issue	September 17, 1999	Preliminary
0.1	Change $V_{DR}(\text{Max.})$ from 3.6V to 5.5V Add 32-pin SOP package Modify 32-pin SOJ package outline drawing and Dimensions	November 30, 1999	
0.2	Add 15ns part Change operating current from 180mA to 150mA (Max.) Change $V_{DR}(\text{Min.})$ from 2V to 3V Remove 32-pin SOP package	January 19, 2000	



# A617308 Series

**Preliminary**

## 128K X 8 BIT HIGH SPEED CMOS SRAM

### Features

- Single + 5V power supply
- Access times: 10/12/15 ns (max.)
- Current: Operating: 150mA (max.)  
Standby: 12mA (max.)
- Full static operation, no clock or refreshing required
- All inputs and outputs are directly TTL compatible
- Common I/O using three-state output
- Data retention voltage: 3V (min.)
- Available in 32-pin SOJ and TSOP packages

### General Description

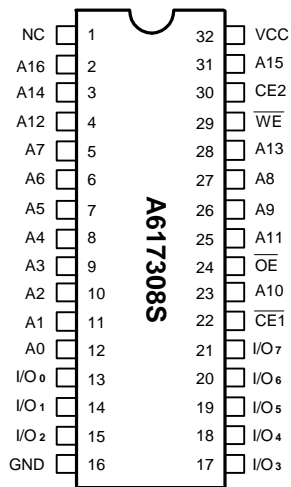
The A617308 is a high-speed, low-power 1,048,576-bit static random access memory organized as 131,072 words by 8 bits and operates on a single 5V power supply. It is built using high performance CMOS process. Inputs and three-state outputs are TTL compatible and allow for direct interfacing with common system bus structures.

Minimum standby power is drawn by this device when chip enable is disable, independent of the other input levels.

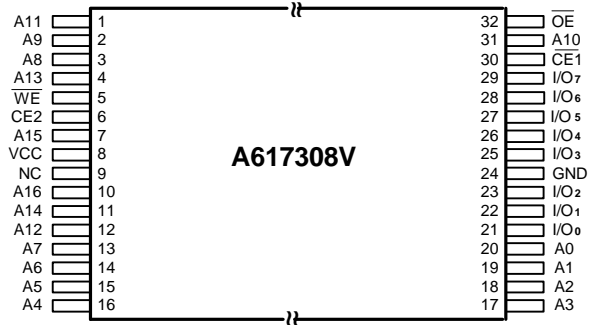
Data retention is guaranteed at a power supply voltage as low as 3V.

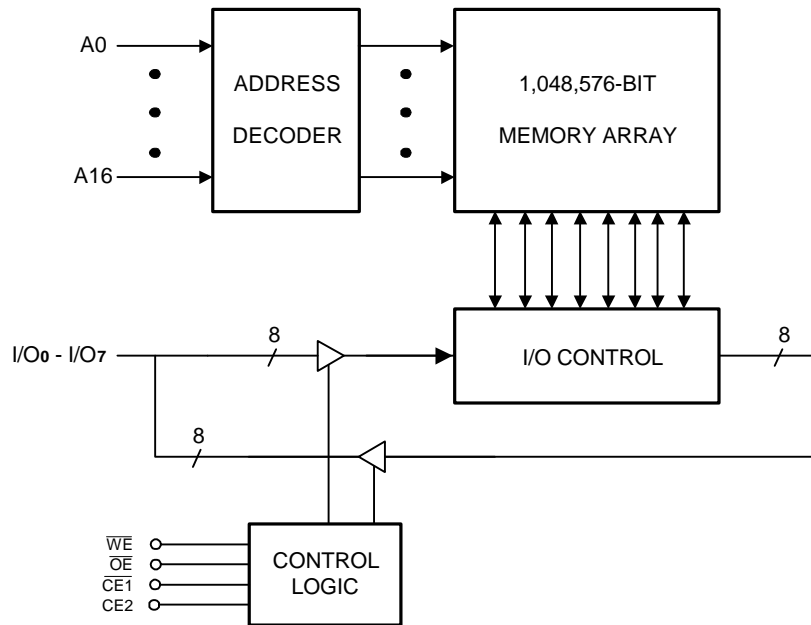
### Pin Configurations

#### ■ SOJ



#### ■ TSOP



**Block Diagram**

**Pin Descriptions – SOJ**

Pin No.	Symbol	Description
2 - 12, 23, 25 - 28, 31	A0 - A16	Address Inputs
13 - 15, 17 - 21	I/O <sub>0</sub> - I/O <sub>7</sub>	Data Inputs/Outputs
22	$\overline{\text{CE1}}$	Chip Enable 1
30	CE2	Chip Enable 2
24	$\overline{\text{OE}}$	Output Enable
29	$\overline{\text{WE}}$	Write Enable
32	VCC	Power Supply
16	GND	Ground
1	NC	No Connection

**Pin Description - TSOP**

Pin No.	Symbol	Description
1 - 4, 7, 10 - 20, 31	A0 - A16	Address Inputs
21 - 23, 25 - 29	I/O <sub>0</sub> - I/O <sub>7</sub>	Data Inputs/Outputs
30	$\overline{\text{CE1}}$	Chip Enable 1
6	CE2	Chip Enable 2
32	$\overline{\text{OE}}$	Output Enable
5	$\overline{\text{WE}}$	Write Enable
8	VCC	Power Supply
24	GND	Ground
9	NC	No Connection



**Recommended DC Operating Conditions**

(T<sub>A</sub> = 0°C to +70°C)

Symbol	Parameter	Min.	Typ.	Max.	Unit
VCC	Supply Voltage	4.5	5.0	5.5	V
GND	Ground	0	0	0	V
V <sub>IH</sub>	Input High Voltage	2.2	-	VCC + 0.5	V
V <sub>IL</sub>	Input Low (1) Voltage	-0.5	0	+0.8	V
C <sub>L</sub>	Output Load	-	-	30	pF

**Absolute Maximum Ratings\***

VCC to GND . . . . . -0.5V to +7V  
 IN, IN/OUT Volt to GND . . . . . -0.5V to VCC +0.5V  
 Operating Temperature, T<sub>opr</sub> . . . . . 0°C to +70°C  
 Storage Temperature, T<sub>stg</sub> . . . . . -55°C to +125°C  
 Temperature Under Bias, T<sub>bias</sub> . . . . . -10°C to +85°C  
 Power Dissipation, P<sub>r</sub> . . . . . 1.0W

**\*Comments**

Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to this device. These are stress ratings only. Functional operation of this device at these or any other conditions above those indicated in the operational sections of this specification is not implied or intended. Exposure to the absolute maximum rating conditions for extended periods may affect device reliability.

**DC Electrical Characteristics** (T<sub>A</sub> = 0°C to +70°C, VCC = 5V ± 10%, GND = 0V)

Symbol	Parameter	A617308-10/12/15		Unit	Conditions
		Min.	Max.		
I <sub>LI</sub>	Input Leakage	-	5	μA	V <sub>IN</sub> = GND to VCC
I <sub>LO</sub>	Output Leakage	-	5	μA	$\overline{CE1} = V_{IH}$ , CE2= V <sub>IL</sub> or $\overline{OE} = V_{IH}$ V <sub>I/O</sub> = GND to VCC
I <sub>CC1</sub> (2)	Dynamic Operating Current	-	150	mA	$\overline{CE1} = V_{IL}$ , CE2 = V <sub>IH</sub> , I <sub>I/O</sub> = 0 mA Min. Cycle, Duty = 100%
I <sub>SB</sub>	Standby Power Supply Current	-	35	mA	$\overline{CE1} = V_{IH}$ or CE2 = V <sub>IL</sub>
I <sub>SB1</sub>		-	12	mA	$\overline{CE1} \geq VCC - 0.2V$ , CE2 ≤ 0.2V V <sub>IN</sub> ≥ VCC -0.2V or V <sub>IN</sub> ≤ 0.2V
V <sub>OL</sub>	Output Low Voltage	-	0.4	V	I <sub>OL</sub> = 8 mA
V <sub>OH</sub>	Output High Voltage	2.4	-	V	I <sub>OH</sub> = -4 mA

Notes: 1. V<sub>IL</sub> = -3.0V for pulses less than 20 ns.  
 2. I<sub>CC1</sub> is dependent on output loading, cycle rates, and Read/Write patterns.

**Truth Table**

Mode	CE1	CE2	OE	WE	I/O Operation	Supply Current
Standby	H	X	X	X	High Z	I <sub>SB</sub> , I <sub>SB1</sub>
	X	L	X	X	High Z	I <sub>SB</sub> , I <sub>SB1</sub>
Output Disable	L	H	H	H	High Z	I <sub>CC1</sub>
Read	L	H	L	H	D <sub>OUT</sub>	I <sub>CC1</sub>
Write	L	H	X	L	D <sub>IN</sub>	I <sub>CC1</sub>

Note: X = H or L

**Capacitance** (T<sub>A</sub> = 25°C, f = 1.0MHz)

Symbol	Parameter	Min.	Max.	Unit	Conditions
C <sub>IN</sub> *	Input Capacitance	-	8	pF	V <sub>IN</sub> = 0V
C <sub>I/O</sub> *	Input/Output Capacitance	-	8	pF	V <sub>I/O</sub> = 0V

\* These parameters are sampled and not 100% tested.

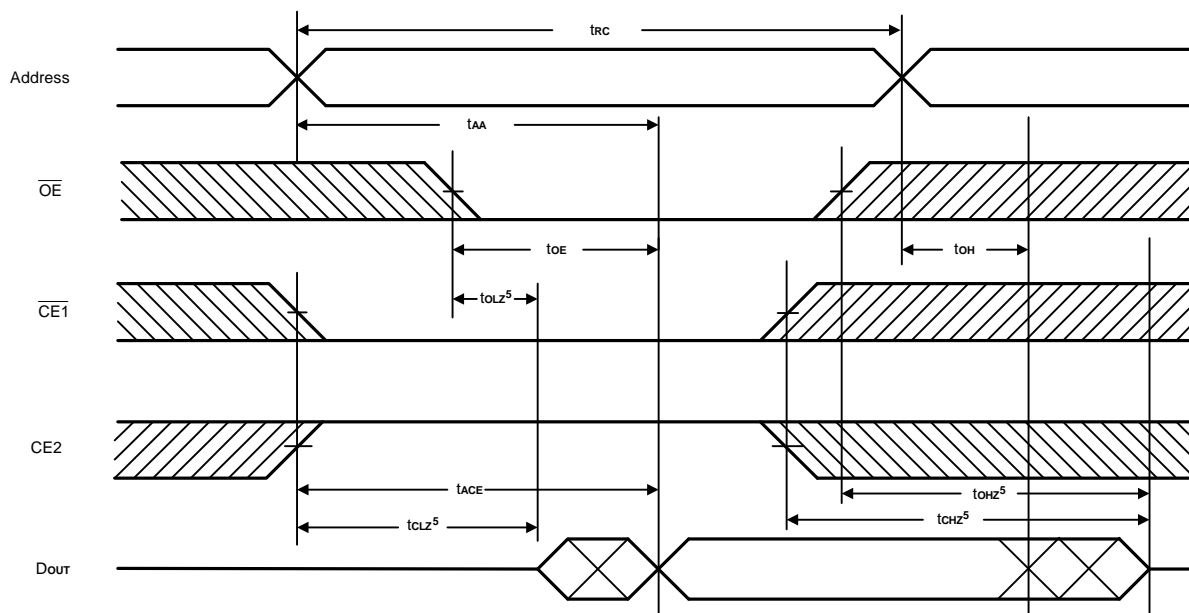
**AC Characteristics** (T<sub>A</sub> = 0°C to +70°C, V<sub>CC</sub> = 5V ± 10%)

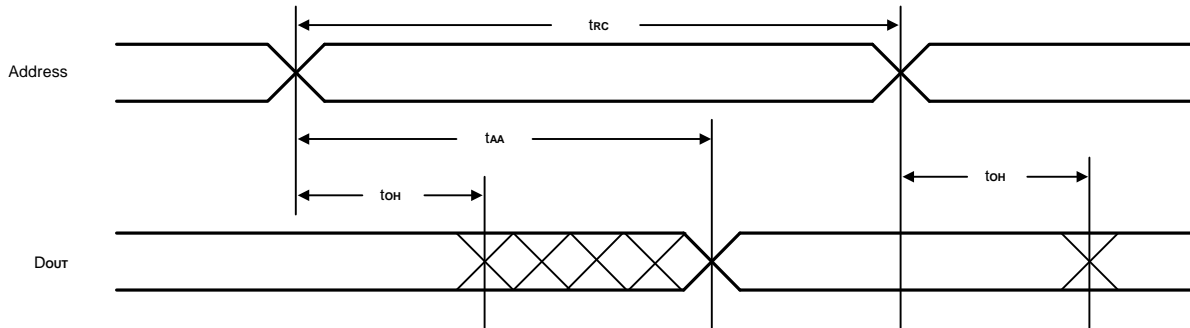
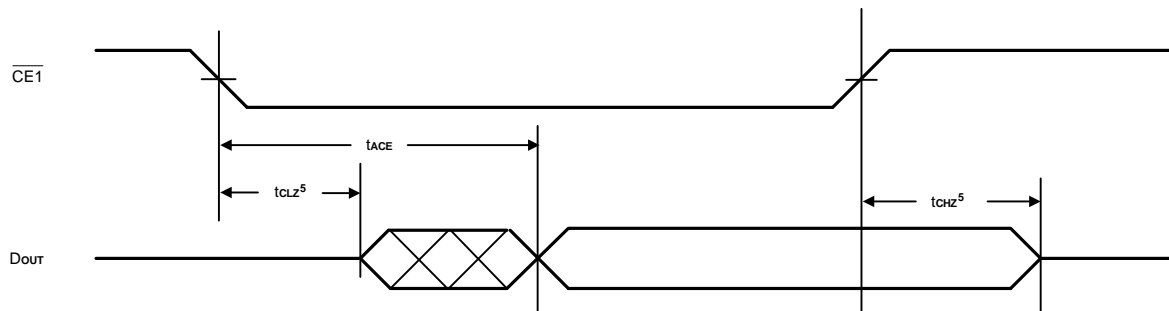
Symbol	Parameter	A617308-10		A617308-12		A617308-15		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	
Read Cycle								
t <sub>RC</sub>	Read Cycle Time	10	-	12	-	15	-	ns
t <sub>AA</sub>	Address Access Time	-	10	-	12	-	15	ns
t <sub>ACE</sub>	Chip Enable Access Time	-	10	-	12	-	15	ns
t <sub>OE</sub>	Output Enable to Output Valid	-	5	-	6	-	8	ns
t <sub>CLZ</sub>	Chip Enable to Output in Low Z	3	-	3	-	3	-	ns
t <sub>OLZ</sub>	Output Enable to Output in Low Z	0	-	0	-	0	-	ns
t <sub>CHZ</sub>	Chip Disable Output in High Z	0	5	0	6	-	8	ns
t <sub>OHZ</sub>	Output Disable to Output in High Z	0	5	0	6	0	8	ns
t <sub>OH</sub>	Output Hold from Address Change	3	-	3	-	3	-	ns

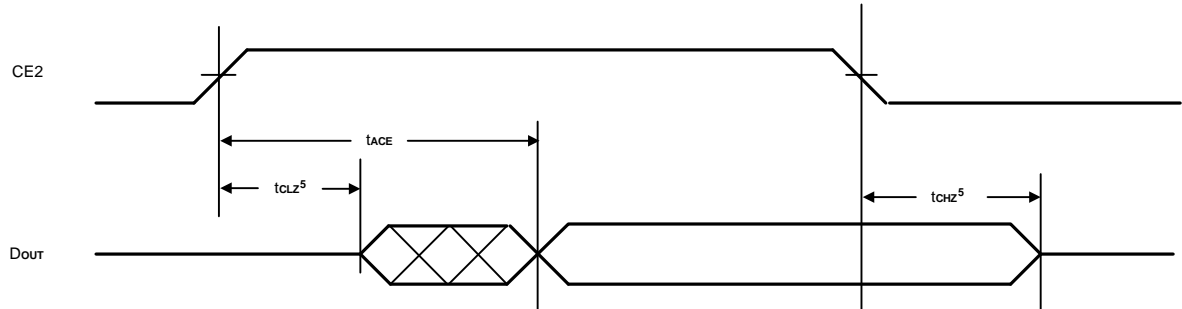
**AC Characteristics (continued)**

Symbol	Parameter	A617308-10		A617308-12		A617308-15		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	
Write Cycle								
t <sub>wc</sub>	Write Cycle Time	10	-	12	-	15	-	ns
t <sub>cw</sub>	Chip Enable to End of Write	9	-	10	-	12	-	ns
t <sub>as</sub>	Address Setup Time of Write	0	-	0	-	0	-	ns
t <sub>aw</sub>	Address Valid to End of Write	9	-	10	-	12	-	ns
t <sub>wp</sub>	Write Pulse Width	9	-	10	-	12	-	ns
t <sub>wr</sub>	Write Recovery Time	0	-	0	-	0	-	ns
t <sub>whz</sub>	Write to Output in High Z	0	5	0	6	0	8	ns
t <sub>dw</sub>	Data to Write Time Overlap	5	-	6	-	7	-	ns
t <sub>dh</sub>	Data Hold from Write Time	0	-	0	-	0	-	ns
t <sub>ow</sub>	Output Active from End of Write	3	-	3	-	3	-	ns

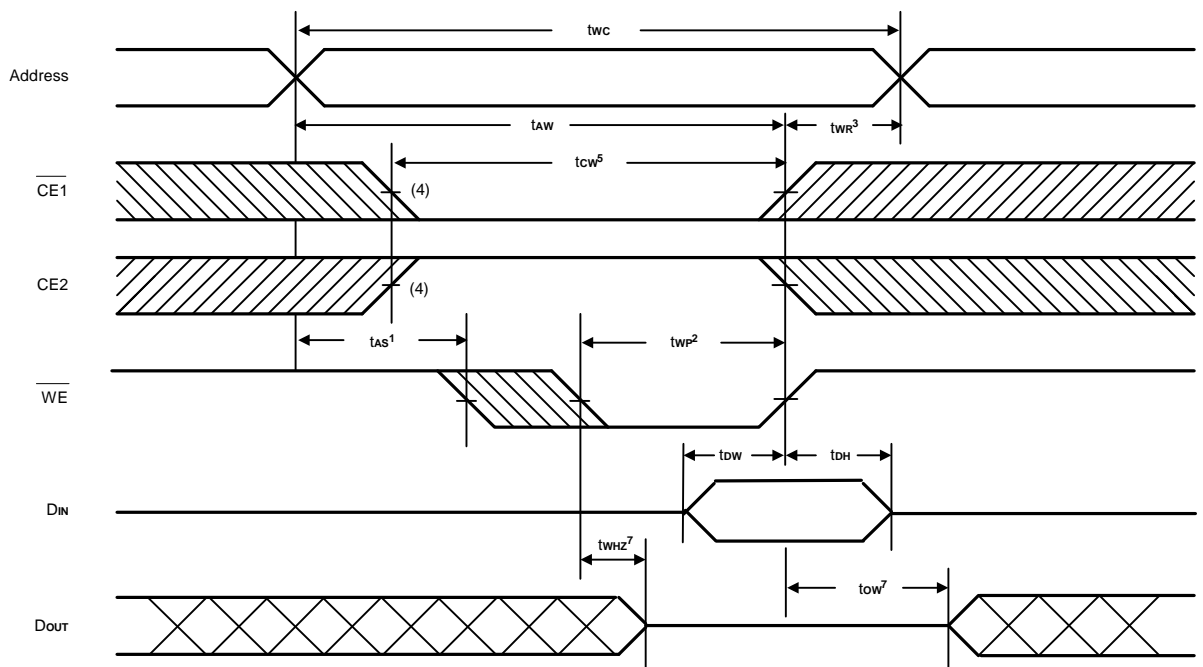
Notes: t<sub>chz</sub>, t<sub>ohz</sub> and t<sub>whz</sub> are defined as the time at which the outputs achieve the open circuit condition and are not referred to output voltage levels.

**Timing Waveforms**
**Read Cycle 1<sup>(1)</sup>**


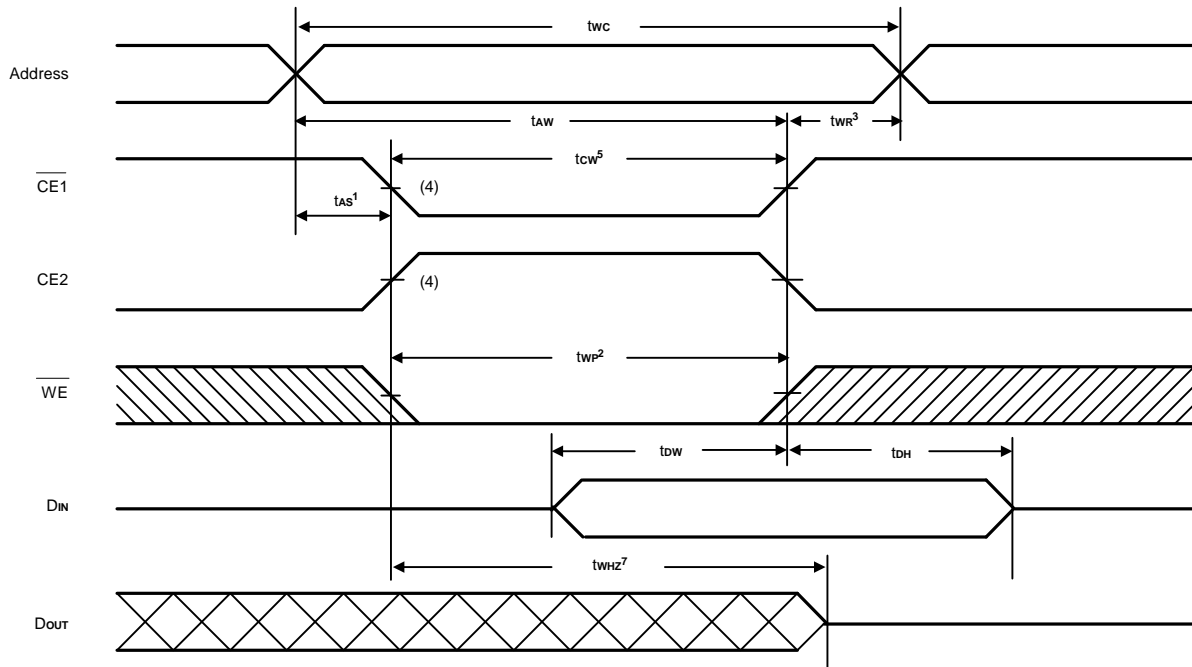
**Timing Waveforms (continued)**
**Read Cycle 2<sup>(1, 2, 4)</sup>**

**Read Cycle 3<sup>(1, 3, 4, 6)</sup>**


**Timing Waveforms (continued)**
**Read Cycle 4<sup>(1, 4, 7, 8)</sup>**


- Notes:
1.  $\overline{WE}$  is high for Read Cycle.
  2. Device is continuously enabled,  $\overline{CE1} = V_{IL}$  and  $CE2 = V_{IH}$
  3. Address valid prior to or coincident with  $\overline{CE1}$  transition low.
  4.  $\overline{OE} = V_{IL}$ .
  5. Transition is measured  $\pm 200\text{mV}$  from steady state. This parameter is sampled and not 100% tested.
  6.  $CE2$  is high.
  7.  $\overline{CE1}$  is low.
  8. Address valid prior to or coincident with  $CE2$  transition high.

**Write Cycle 1<sup>(6)</sup>**
**(Write Enable Controlled)**


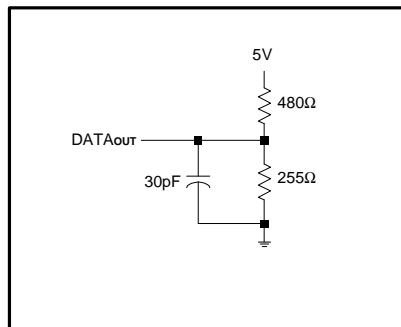
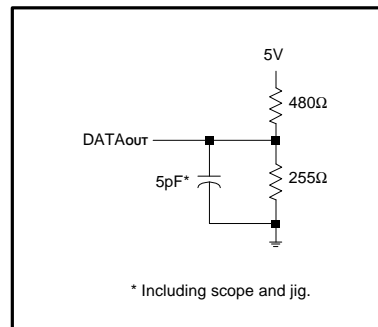


**Timing Waveforms (continued)**
**Write Cycle 2**
**(Chip Enable Controlled)**


- Notes:
1.  $t_{as}$  is measured from the address valid to the beginning of Write.
  2. A Write occurs during the overlap ( $t_{wp}$ ) of a low  $\overline{CE1}$ , a high CE2 and a low  $\overline{WE}$ .
  3.  $t_{wr}$  is measured from the earliest of  $\overline{CE1}$  or  $\overline{WE}$  going high or CE2 going low to the end of the Write cycle.
  4. If the  $\overline{CE1}$  low transition or the CE2 high transition occurs simultaneously with the  $\overline{WE}$  low transition or after the  $\overline{WE}$  transition, outputs remain in a high impedance state.
  5.  $t_{cw}$  is measured from the later of  $\overline{CE1}$  going low or CE2 going high to the end of Write.
  6.  $\overline{OE}$  is continuously low. ( $\overline{OE} = V_{IL}$ )
  7. Transition is measured  $\pm 200\text{mV}$  from steady state. This parameter is sampled and not 100% tested.

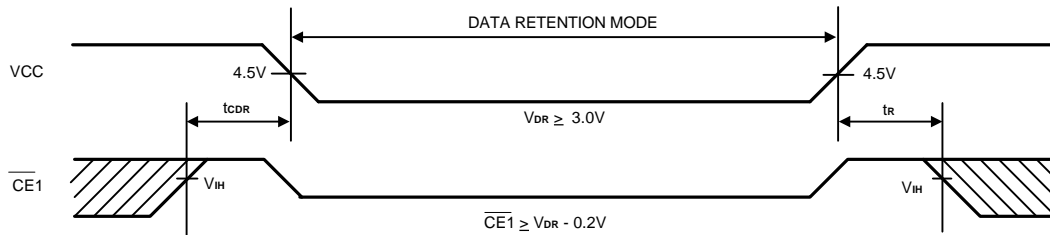
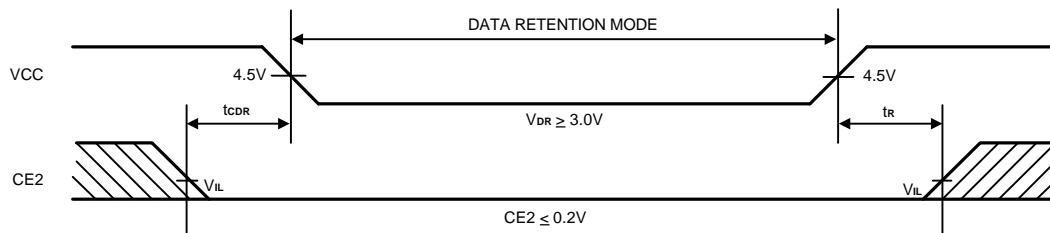
**AC Test Conditions**

Input Pulse Levels	0V to 3.0V
Input Rise and Fall Time	2 ns
Input and Output Timing Reference Levels	1.5V
Output Load	See Figures 1 and 2


**Figure 1. Output Load**

**Figure 2. Output Load for  $t_{CLZ}$ ,  $t_{OLZ}$ ,  $t_{CHZ}$ ,  $t_{OHZ}$ ,  $t_{WHZ}$ , and  $t_{OW}$** 
**Data Retention Characteristics** ( $T_A = 0^\circ\text{C}$  to  $70^\circ\text{C}$ )

Symbol	Parameter	Min.	Max.	Unit	Conditions
$V_{DR}$	VCC for Data Retention	3	5.5	V	$\overline{CE1} \geq VCC - 0.2V$
$I_{CCDR}$	Data Retention Current	-	1	mA	$VCC = 3.0V$ $\overline{CE1} \geq VCC - 0.2V$ $CE2 \leq 0.2V$ $V_{IN} \geq VCC - 0.2V$ or $V_{IN} \leq 0.2V$
$t_{CDR}$	Chip Disable to Data Retention Time	0	-	ns	See Retention Waveform
$t_R$	Operation Recovery Time	$T_{RC}^*$	-	ms	

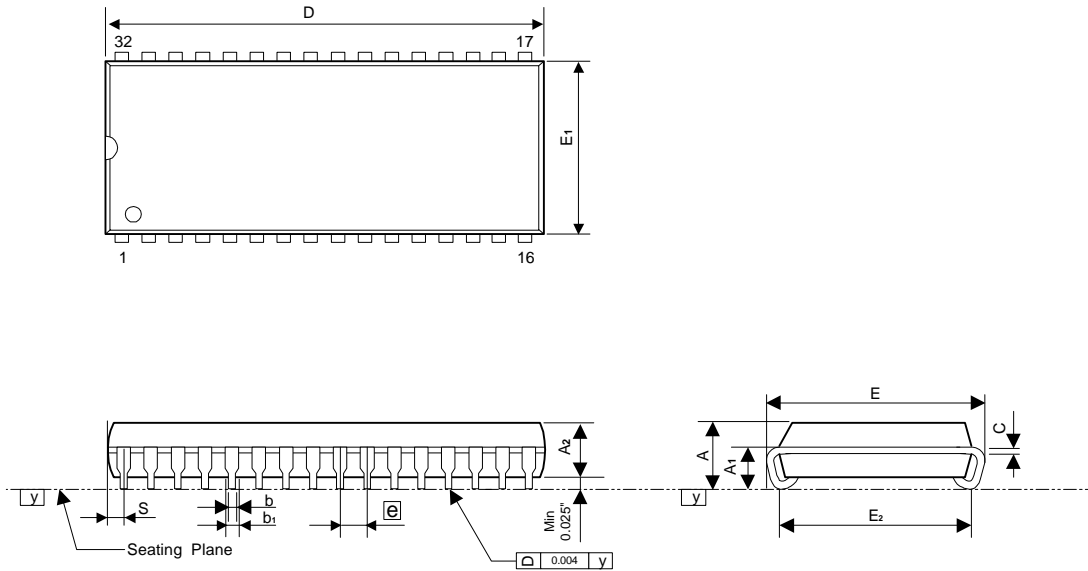
 $t_{RC}$  = Read Cycle Time

**Low VCC Data Retention Waveform (1) ( $\overline{CE1}$  controlled)**

**Low VCC Data Retention Waveform (2) (CE2 controlled)**

**Ordering Information**

Part No.	Access Time (ns)	Operating Current Max. (mA)	Standby Current Max. (mA)	Package
A617308S-10	10	150	12	32L SOJ
A617308S-12	12	150	12	32L SOJ
A617308S-15	15	150	12	32L SOJ
A617308V-10	10	150	12	32L TSOP
A617308V-12	12	150	12	32L TSOP
A617308V-15	15	150	12	32L TSOP

**Package Information**
**SOJ 32L Outline Dimensions**

unit: inches/mm



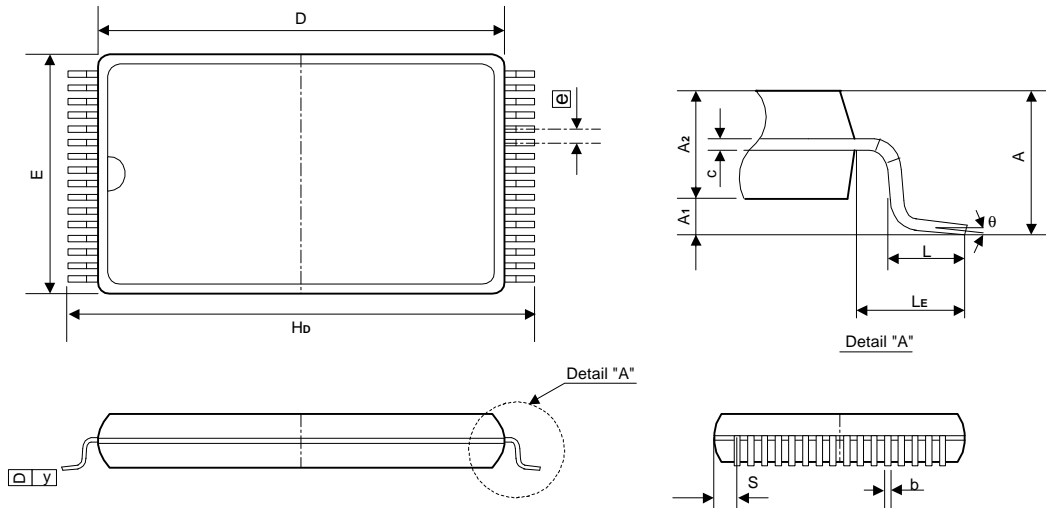
Symbol	Dimensions in inches			Dimensions in mm		
	Min	Nom	Max	Min	Nom	Max
A	0.128	0.132	0.140	3.25	3.35	3.56
A1	0.052	-	-	2.08	-	-
A2	0.095	0.100	0.105	2.41	2.54	2.67
b	0.016	0.018	0.020	0.41	0.46	0.51
b1	0.026	0.028	0.032	0.66	0.71	0.81
C	0.006	0.008	0.012	0.15	0.20	0.30
D	0.820	0.825	0.830	20.83	20.96	21.08
E	0.330	0.335	0.340	8.39	8.51	8.63
E1	0.295	0.300	0.305	7.49	7.62	7.75
E2	0.260	0.267	0.274	6.61	6.78	6.96
e	-	0.050	-	-	1.27	-
S	-	-	0.048	-	-	1.22
y	-	-	0.004	-	-	0.10

**Notes:**

1. The maximum value of dimension D includes end flash.
2. Dimension E does not include resin fins.
3. Dimension E1 is for PC Board surface mount pad pitch design reference only.
4. Dimension S includes end flash.

**Package Information**
**TSOP 32L TYPE I (8 X 20mm) Outline Dimensions**

unit: inches/mm



Symbol	Dimensions in inches			Dimensions in mm		
	Min	Nom	Max	Min	Nom	Max
A	-	-	0.047	-	-	1.20
A <sub>1</sub>	0.002	-	0.006	0.05	-	0.15
A <sub>2</sub>	0.037	0.039	0.041	0.95	1.00	1.05
b	0.007	0.009	0.011	0.18	0.22	0.27
c	0.004	-	0.008	0.11	-	0.20
D	0.720	0.724	0.728	18.30	18.40	18.50
E	-	0.315	0.319	-	8.00	8.10
[e]	0.020 BSC			0.50 BSC		
Hd	0.779	0.787	0.795	19.80	20.00	20.20
L	0.016	0.020	0.024	0.40	0.50	0.60
LE	-	0.032	-	-	0.80	-
S	-	-	0.020	-	-	0.50
y	-	-	0.003	-	-	0.08
θ	0°	-	5°	0°	-	5°

**Notes:**

1. The maximum value of dimension D includes end flash.
2. Dimension E does not include resin fins.
3. Dimension S includes end flash.